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Facility at SLAC to Pair Petawatt System with X-Ray FEL

.: Top Stories

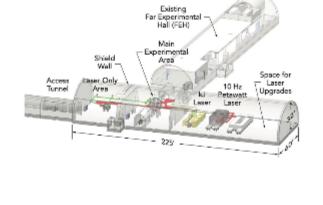
A new facility at the U.S. Department of Energy's SLAC National

Accelerator Laboratory will combine a petawatt laser system with an xray free-electron laser (XFEL) to further the scientific understanding of matter in extreme conditions. Coupled to the lab's Linac Coherent Light Source (LCLS), the Matter in Extreme Conditions Upgrade (MEC-U) received approval from the DOE Office of Science to begin preliminary design and execution. Read Article

Engineering researchers at the University of Arkansas received \$17.87 million from the NSF to build and operate a national silicon carbide research and fabrication facility. The open-access facility will fill a gap in U.S. production of integrated circuits made with silicon carbide.

NSF Allots \$18M for National Semiconductor Fab

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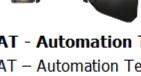
NIL Technologies Reports 94% Efficiency in Meta-Optical Lens Optical solutions company NIL Technology (NILT) reports that is has

designed, built, and characterized multiple meta-optical element (MOE) lenses with 94% absolute efficiency. The demonstration was done with 940-nm NIR lens, with results being heralded as a major milestone for the commercial use of metalenses. Read Article



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AT - Automation Technology GmbH AT – Automation Technology revolutionized the 3D

sensor, laser, and link modules and recently launched the new cx4090HS 3D sensor module which supplements the MCS series. Visit Website Request Info

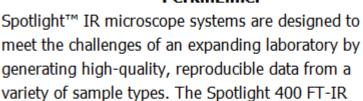
sensor industry with its modular 3D compact sensor

(MCS) which is based on a modular system of

Weld Monitor

MM-L300A Desktop Laser

AMADA WELD TECH INC. AMADA WELD TECH'S MM-



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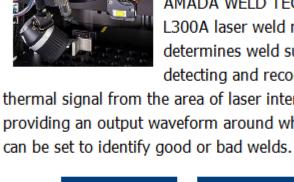
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Test

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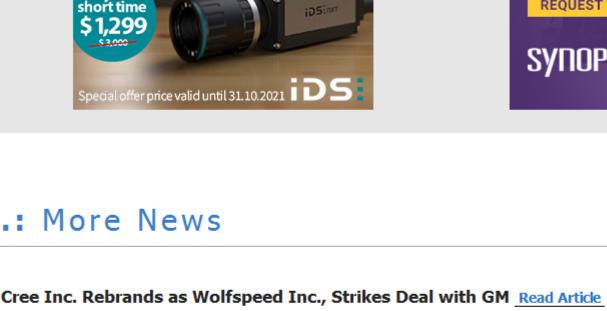
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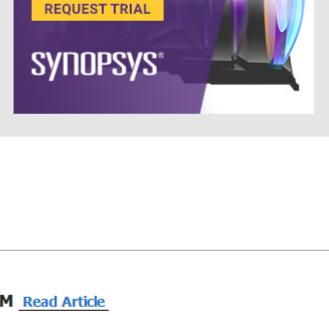
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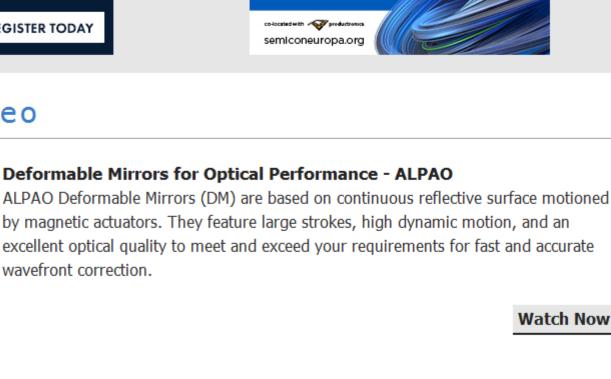
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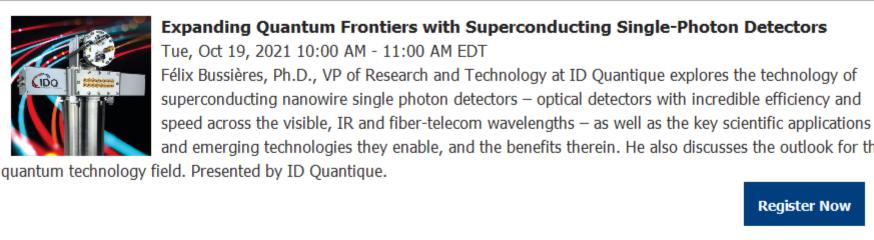


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Upcoming Webinars



Tue, Oct 19, 2021 10:00 AM - 11:00 AM EDT Félix Bussières, Ph.D., VP of Research and Technology at ID Quantique explores the technology of

and emerging technologies they enable, and the benefits therein. He also discusses the outlook for the

from R&D to production can be ensured and optimized.

Ensuring Manufacturing Process Success in Laser Microwelding Thu, Oct 21, 2021 1:00 PM - 2:00 PM EDT This webinar with Mark Boyle, Ph.D., Senior Manager for Product Engineering and Applications at AMADA WELD TECH INC., covers several key factors to consider in laser microwelding process development and measurement before, during, and after a weld. Boyle discusses how the transition

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